



# TK11A60D

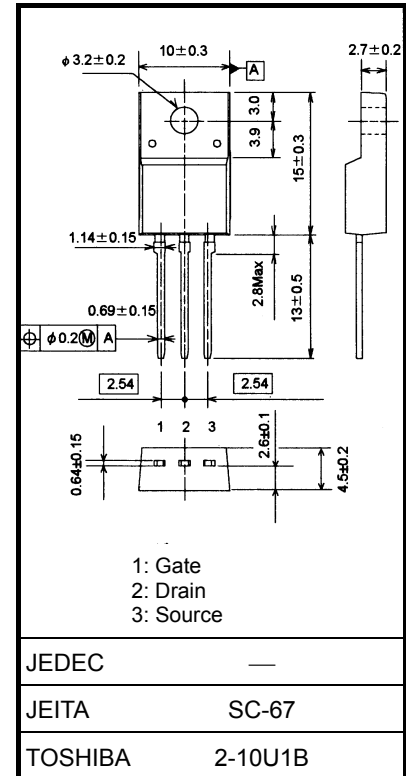
## Switching Regulator Applications

Unit: mm

- Low drain-source ON resistance:  $R_{DS(ON)} = 0.54 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 6.0 \text{ S}$  (typ.)
- Low leakage current:  $I_{DSS} = 10 \mu\text{A}$  (max) ( $V_{DS} = 600 \text{ V}$ )
- Enhancement-mode:  $V_{th} = 2.0$  to  $4.0 \text{ V}$  ( $V_{DS} = 10 \text{ V}$ ,  $I_D = 1 \text{ mA}$ )

## Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	600	V
Gate-source voltage		$V_{GSS}$	$\pm 30$	V
Drain current	DC (Note 1)	$I_D$	11	A
	Pulse (Note 1)	$I_{DP}$	44	
Drain power dissipation ( $T_c = 25^\circ\text{C}$ )		$P_D$	45	W
Single pulse avalanche energy (Note 2)		$E_{AS}$	396	mJ
Avalanche current		$I_{AR}$	11	A
Repetitive avalanche energy (Note 3)		$E_{AR}$	4.5	mJ
Channel temperature		$T_{ch}$	150	$^\circ\text{C}$
Storage temperature range		$T_{stg}$	-55 to 150	$^\circ\text{C}$



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

## Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th(ch-c)}$	2.78	$^\circ\text{C/W}$
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	62.5	$^\circ\text{C/W}$

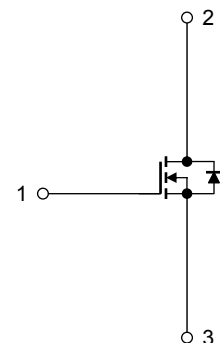
Note 1: Please use devices on conditions that the channel temperature is below  $150^\circ\text{C}$ .

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^\circ\text{C}$  (initial),  $L = 5.73 \text{ mH}$ ,  $R_G = 25 \Omega$ ,  $I_{AR} = 11 \text{ A}$

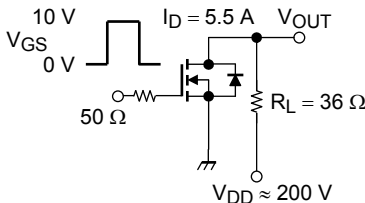
Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

Internal Connection



**Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		$I_{GSS}$	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	—	—	$\pm 1$	$\mu\text{A}$
Drain cut-off current		$I_{DSS}$	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	—	—	10	$\mu\text{A}$
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	600	—	—	V
Gate threshold voltage		$V_{th}$	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	2.0	—	4.0	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}, I_D = 5.5 \text{ A}$	—	0.54	0.65	$\Omega$
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10 \text{ V}, I_D = 5.5 \text{ A}$	1.5	6.0	—	S
Input capacitance		$C_{iss}$	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	—	1550	—	pF
Reverse transfer capacitance		$C_{rss}$		—	7	—	
Output capacitance		$C_{oss}$		—	165	—	
Switching time	Rise time	$t_r$		—	25	—	ns
	Turn-on time	$t_{on}$		—	60	—	
	Fall time	$t_f$		—	15	—	
	Turn-off time	$t_{off}$		—	110	—	
Total gate charge		$Q_g$	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 11 \text{ A}$	—	28	—	nC
Gate-source charge		$Q_{gs}$		—	18	—	
Gate-drain charge		$Q_{gd}$		—	10	—	

**Source-Drain Ratings and Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	—	—	—	11	A
Pulse drain reverse current (Note 1)	$I_{DRP}$	—	—	—	44	A
Forward voltage (diode)	$V_{DSF}$	$I_{DR} = 11 \text{ A}, V_{GS} = 0 \text{ V}$	—	—	-1.7	V
Reverse recovery time	$t_{rr}$	$I_{DR} = 11 \text{ A}, V_{GS} = 0 \text{ V},$ $dI_{DR}/dt = 100 \text{ A}/\mu\text{s}$	—	1300	—	ns
Reverse recovery charge	$Q_{rr}$		—	13	—	$\mu\text{C}$

**Marking**